Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	r	
10/092,064	MICHAEL D. SCHOLTEN		
Examiner	Art Unit		
Binh Q. Nguyen	2664		

SEARCHED					
Class	Subclass	Date	Examiner		
370	412	11/9/2005	BQN		
370	236.1	11/9/2005	BQN		
370	299	11/9/2005	BQN		
709	250	11/9/2005	BQN		
398	59	11/9/2005	BQN		
375	233	11/9/2005	BQN		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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(INCLUDING SEARCH	DATE	EXMR
	5/112	
EAST (US-GPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM-TDB), see more on search history.	11/9/2005	BQN
Consulted with Wellington Chin	11/9/2005	BQN
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